Form PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

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PAPPLICANT
KUNAL R. PAREKH, ET AL.

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				U.S. PATENT DOCUMENTS		_			
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yll	AA	5,338,700	08/94	Dennison et al.					
0	АВ	5,401,681	03/95	Dennison					
	AC	6,015,983	01/00	Parekh					
	AD	5,981,334	11/99	Chien et al.					
	AE	5,981,333		Parekh et al					
	AF	5,923,973	07/99	Chen et al.	*				
1	AG	5,913,129	06/99	Wu et al.					
	АН	5,885,866	03/99	Chen					
	AI	5,874,335	02/99	Jenq et al.	ć			•	
	AJ	5,763,286	06/98	Figura et al.					
yy	AK	6,037,220	03/00	Chien et al.					
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	AR			NCES (including Author, Title, Date,		Symposium			
y/		Aoki, Masami, et al., "Fully Self-Aligned 6F <sup>2</sup> Cell Technology For Low Cost 1 Gb DRAM", Symposium  On VLSI Technology Digest of Technical Papers, IEEE, pp. 22-23 (1996)							
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered Include copy of this form with next communication to applicant.



Sheet 2 of 2

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W	AA	6.034.391	03/00	Tobita						
	AB	5,897,352	04/99	Lin et al.						
	AC	5,745,336	04/98	Saito et al.						
	AD	5,686,747	11/97	Jost et al.						
	AE	5,383,150	01/95	Nakamura et al.						
	AF	5,786,250	07/98	Wu et al.						
	AG	5,597,756	01/97	Fazan et al.				-		
	АН	5,639,689	06/97	Woo						
	AI	5,663,085	09/97	Tanigawa						
	AJ	5,418,180	05/95	Brown				-		
N.	AK	5.340,765	08/94	Dennison et al.						
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